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Application/Control No.	Applicant(s)/Patent under Reexamination
10/608,761	WIEROWSKI, JAMES V.
Examiner	Art Unit
Le Nguyen	2174

SEARCHED				
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715	712	3/10/2007	LVN	

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	b, USPAT: /712	3/10/2007	LVN

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inventor name search	3/10/2007	LVN
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